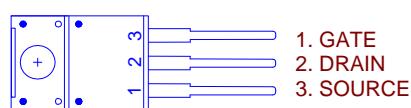
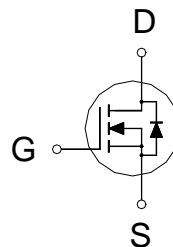


NIKO-SEM

**N-Channel Enhancement Mode
Field Effect Transistor** P1060ETF:TO-220F
P1060ETFS:TO-220FS
Halogen-Free & Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
600V	0.75Ω	10A

**100% UIS tested****ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	600	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current ²	I_D	10	A
		6	
Pulsed Drain Current ^{1, 2}	I_{DM}	30	A
Avalanche Current ³	I_{AS}	3.5	
Avalanche Energy ³	E_{AS}	61	mJ
Power Dissipation	P_D	39	W
		15	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		3.2	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

¹Pulse width limited by maximum junction temperature.²Limited only by maximum temperature allowed³ $V_{DD} = 100\text{V}$, $L = 10\text{mH}$, starting $T_J = 25^\circ\text{C}$ **ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}$, $I_D = 250\mu\text{A}$	600			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$	2	2.9	4	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}$, $V_{GS} = \pm 30\text{V}$			± 100	nA

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Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 600V, V_{GS} = 0V, T_C = 25^\circ C$			1	μA
		$V_{DS} = 480V, V_{GS} = 0V, T_C = 100^\circ C$			10	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 5A$		0.57	0.75	Ω
Forward Transconductance ¹	g_{fs}	$V_{DS} = 15V, I_D = 5A$		15		S

DYNAMIC

Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	1552		pF
Output Capacitance	C_{oss}		162		
Reverse Transfer Capacitance	C_{rss}		23		
Total Gate Charge ²	Q_g	$V_{DD} = 480V, I_D = 10A, V_{GS} = 10V$	49		nC
Gate-Source Charge ²	Q_{gs}		7		
Gate-Drain Charge ²	Q_{gd}		20		
Turn-On Delay Time ²	$t_{d(on)}$		60		
Rise Time ²	t_r	$V_{DD} = 300V, I_D = 10A, R_G = 25\Omega$	34		nS
Turn-Off Delay Time ²	$t_{d(off)}$		220		
Fall Time ²	t_f		47		

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)

Continuous Current ³	I_S			10	A
Forward Voltage ¹	V_{SD}	$I_F = 10A, V_{GS} = 0V$		1.5	V
Reverse Recovery Time	t_{rr}	$I_F = 10A, dI_F/dt = 100A / \mu S$	404		nS
Reverse Recovery Charge	Q_{rr}		4.7		

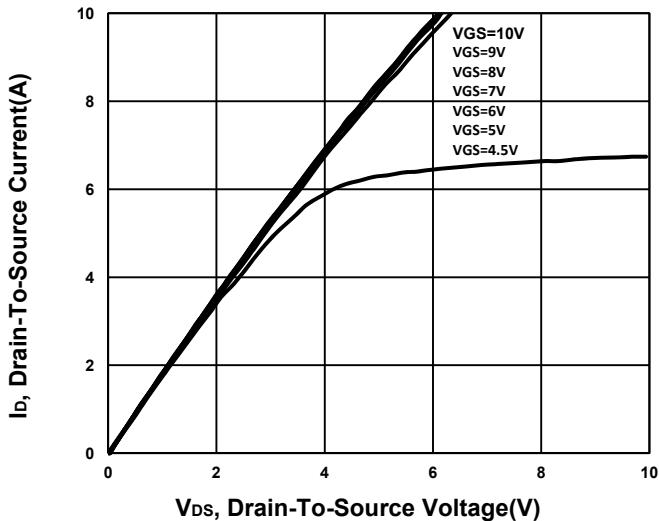
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.

NIKO-SEM

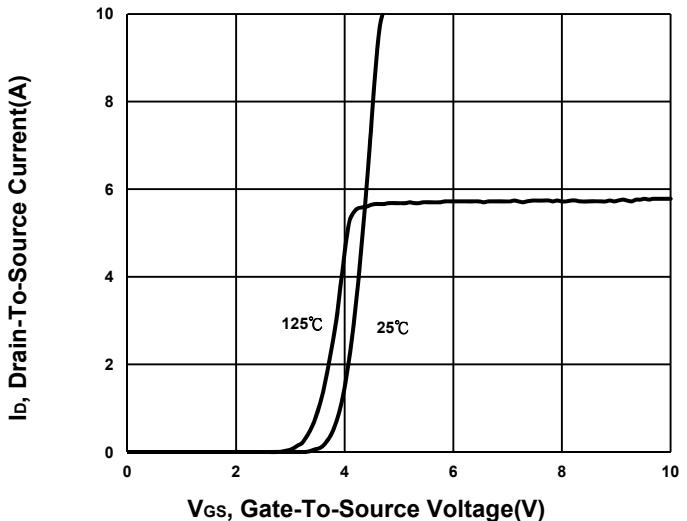
N-Channel Enhancement Mode Field Effect Transistor

**P1060ETF:TO-220F
P1060ETFS:TO-220FS
Halogen-Free & Lead-Free**

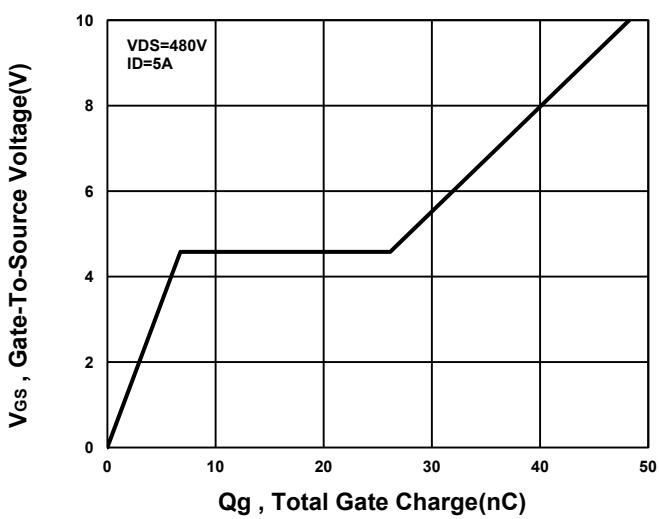
Output Characteristics



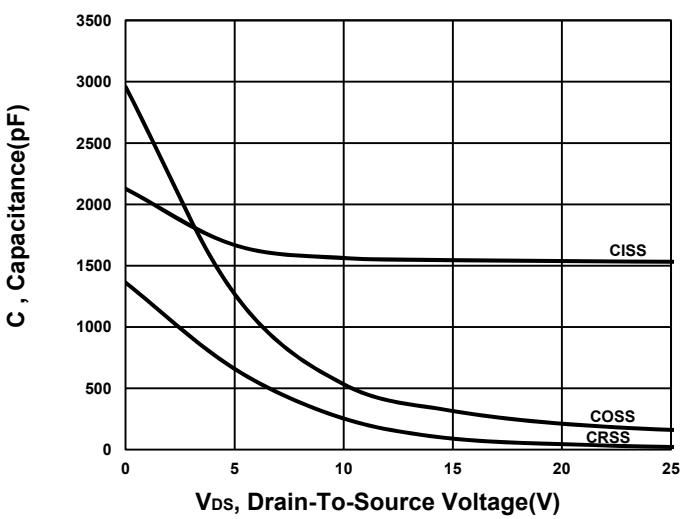
Transfer Characteristics



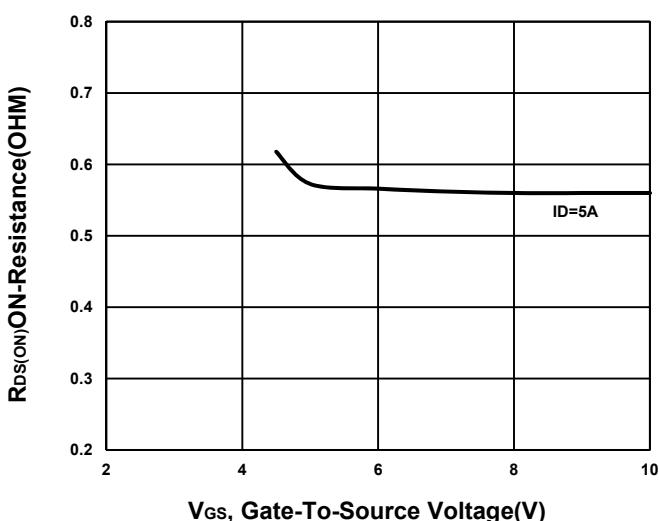
Gate charge Characteristics



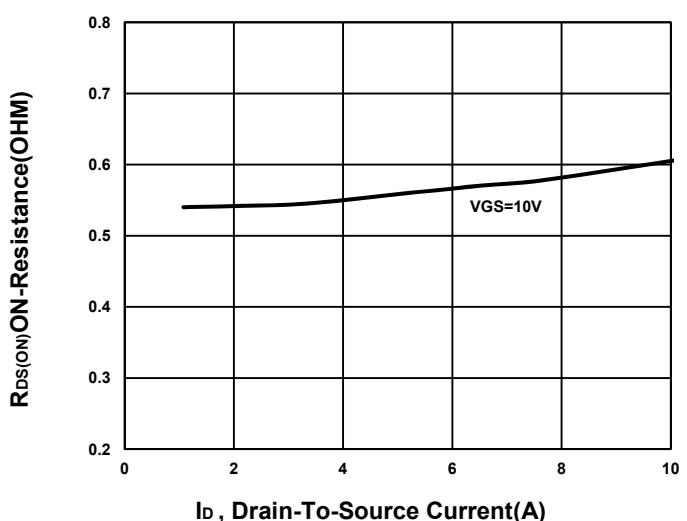
Capacitance Characteristic



On-Resistance VS Gate-To-Source



On-Resistance VS Drain Current

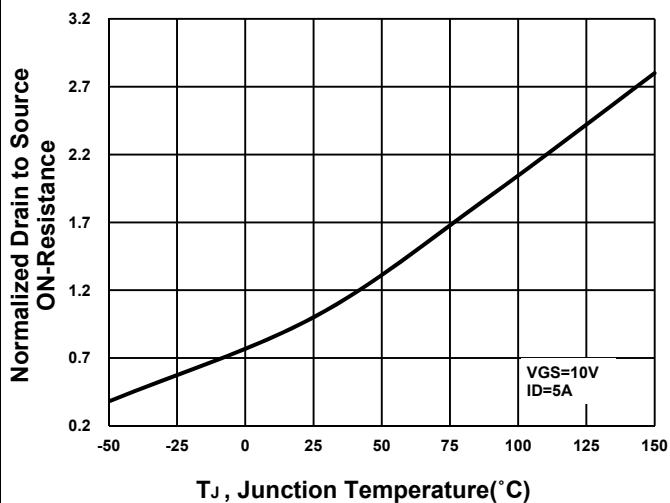


NIKO-SEM

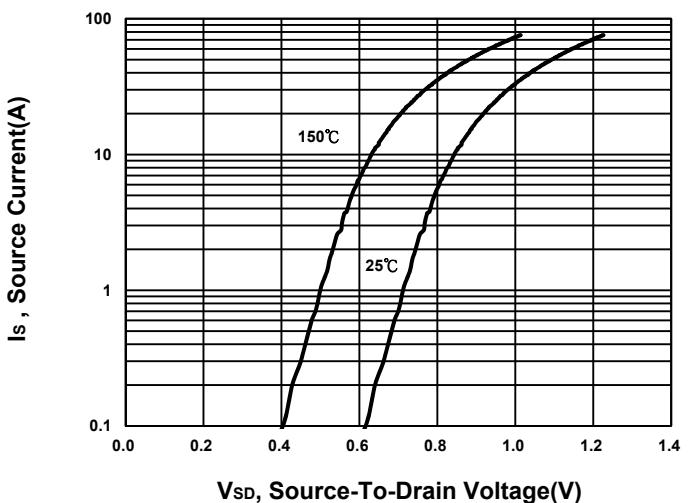
N-Channel Enhancement Mode Field Effect Transistor

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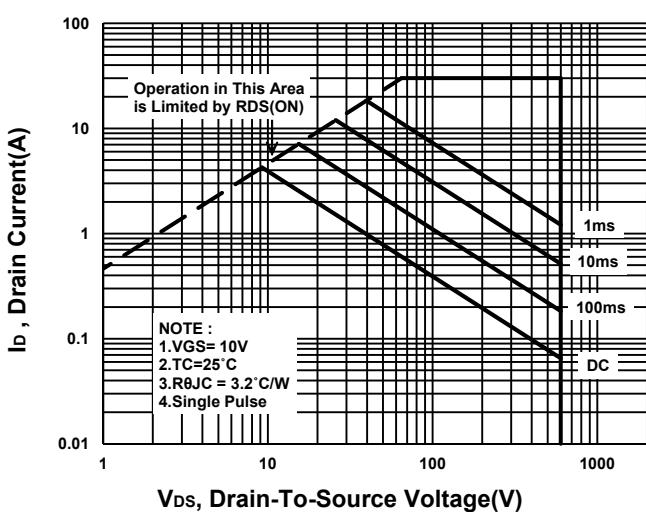
On-Resistance VS Temperature



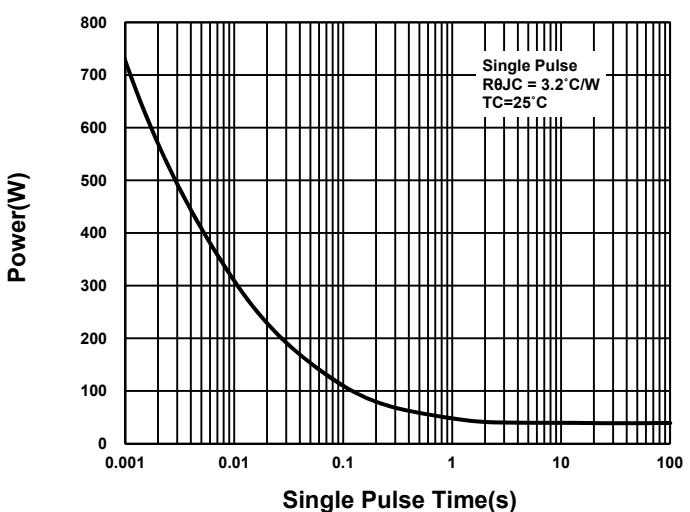
Source-Drain Diode Forward Voltage



Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

